

SEMiX604GB17E4s



SEMIX604GB17E4s

Features

- Homogeneous Si
- Trench = Trenchgate technology
- $V_{CE(sat)}$ with positive temperature coefficient
- High short circuit capability
- UL recognized, file no. E63532

Typical Applications*

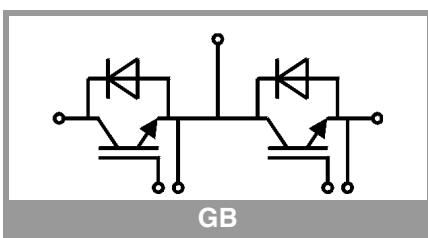
- AC inverter drives
- UPS
- Electronic Welding

Remarks

- Case temperature limited to $T_C=125^\circ\text{C}$ max.
- Product reliability results are valid for $T_j=150^\circ\text{C}$
- Dynamic values apply to the following combination of resistors:
 $R_{Gon,\text{main}} = 1,3/0,3 \Omega$ ($V_{cc}=1200\text{V}/900\text{V}$)
 $R_{Goff,\text{main}} = 1,3/0,3 \Omega$ ($V_{cc}=1200\text{V}/900\text{V}$)
 $R_{G,X} = 2,2 \Omega$
 $R_{E,X} = 0,5 \Omega$

Absolute Maximum Ratings		Values	Unit
Symbol	Conditions		
IGBT			
V_{CES}	$T_j = 25^\circ\text{C}$	1700	V
I_c	$T_j = 175^\circ\text{C}$	1015	A
		772	A
I_{Cnom}		600	A
I_{CRM}	$I_{CRM} = 3 \times I_{Cnom}$	1800	A
V_{GES}		-20 ... 20	V
t_{psc}	$V_{CC} = 1000\text{ V}$ $V_{GE} \leq 15\text{ V}$ $V_{CES} \leq 1700\text{ V}$	10	μs
T_j		-40 ... 175	$^\circ\text{C}$
Inverse diode			
V_{RRM}	$T_j = 25^\circ\text{C}$	1700	V
I_F	$T_j = 175^\circ\text{C}$	629	A
		463	A
I_{Fnom}		600	A
I_{FRM}	$I_{FRM} = 2 \times I_{Fnom}$	1200	A
I_{FSM}	$t_p = 10\text{ ms}, \sin 180^\circ, T_j = 25^\circ\text{C}$	3420	A
T_j		-40 ... 175	$^\circ\text{C}$
Module			
$I_{t(\text{RMS})}$		600	A
T_{stg}		-40 ... 125	$^\circ\text{C}$
V_{isol}	AC sinus 50Hz, $t = 1\text{ min}$	4000	V

Symbol	Conditions	min.	typ.	max.	Unit
IGBT					
$V_{CE(\text{sat})}$	$I_c = 600\text{ A}$ $V_{GE} = 15\text{ V}$ chiplevel	1.90	2.20	2.45	V
		2.26			
V_{CE0}	chiplevel	1.1	1.2	1.3	V
		1	1.1	1.2	
r_{CE}	$V_{GE} = 15\text{ V}$ chiplevel	1.3	1.7	2.1	$\text{m}\Omega$
		2.1	2.3	2.5	
$V_{GE(\text{th})}$	$V_{GE} = V_{CE}, I_c = 24\text{ mA}$	5.2	5.8	6.4	V
I_{CES}	$V_{GE} = 0\text{ V}$ $V_{CE} = 1700\text{ V}$		5	mA	
			mA		
C_{ies}	$V_{CE} = 25\text{ V}$ $f = 1\text{ MHz}$	48	nF		
C_{oes}	$V_{GE} = 0\text{ V}$ $f = 1\text{ MHz}$	2.00	nF		
C_{res}	$f = 1\text{ MHz}$	1.52	nF		
Q_G	$V_{GE} = -8\text{ V} \dots +15\text{ V}$	4800	nC		
R_{Gint}	$T_j = 25^\circ\text{C}$	1.25	Ω		
$t_{d(on)}$	$V_{CC} = 1200\text{ V}$ $I_c = 600\text{ A}$	390	ns		
t_r	$V_{GE} = +15/-15\text{ V}$	60	ns		
E_{on}	$R_{G\text{ on}} = 2\Omega$	255	mJ		
$t_{d(off)}$	$R_{G\text{ off}} = 2\Omega$	920	ns		
t_f	$dI/dt_{on} = 9930\text{ A}/\mu\text{s}$	180	ns		
	$dI/dt_{off} = 2750\text{ A}/\mu\text{s}$				
E_{off}	$dU/dt = 5150\text{ V}/\mu\text{s}$ $L_s = 30\text{ nH}$	255	mJ		



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Characteristics		min.	typ.	max.	Unit
Symbol	Conditions				
$t_{d(on)}$	$V_{CC} = 900 \text{ V}$ $I_C = 600 \text{ A}$ $V_{GE} = +15/-15 \text{ V}$ $R_{G\ on} = 1 \Omega$ $R_{G\ off} = 1 \Omega$ $di/dt_{on} = 6500 \text{ A}/\mu\text{s}$ $di/dt_{off} = 2300 \text{ A}/\mu\text{s}$ E_{off} $L_s = 80 \text{ nH}$	$T_j = 150 \text{ }^\circ\text{C}$ $T_j = 150 \text{ }^\circ\text{C}$	330 90 49 800 230 213	330 90 49 800 230 213	ns ns mJ ns ns mJ
t_f	$du/dt = 4300 \text{ V}/\mu\text{s}$				
$R_{th(j-c)}$	per IGBT			0.042	K/W

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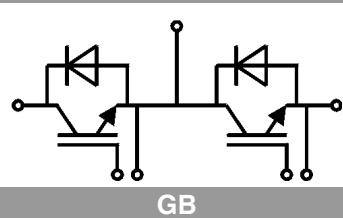
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Characteristics		min.	typ.	max.	Unit
Symbol	Conditions				
Inverse diode					
$V_F = V_{EC}$	$I_F = 600 \text{ A}$ $V_{GE} = 0 \text{ V}$ chiplevel	$T_j = 25 \text{ }^\circ\text{C}$ $T_j = 150 \text{ }^\circ\text{C}$	1.98 2.11	2.37 2.52	V
V_{FO}	chiplevel	$T_j = 25 \text{ }^\circ\text{C}$ $T_j = 150 \text{ }^\circ\text{C}$	1.16 1.08	1.32 1.22	V
r_F	chiplevel	$T_j = 25 \text{ }^\circ\text{C}$ $T_j = 150 \text{ }^\circ\text{C}$	0.9 1.7	1.1 2.2	mΩ
I_{RRM}	$I_F = 600 \text{ A}$ $di/dt_{off} = 7700 \text{ A}/\mu\text{s}$	$T_j = 150 \text{ }^\circ\text{C}$	560	A	
Q_{rr}	$V_{GE} = -15 \text{ V}$ $V_R = 1200 \text{ V}$	$T_j = 150 \text{ }^\circ\text{C}$	210	μC	
E_{rr}	$V_{GE} = -15 \text{ V}$ $V_R = 900 \text{ V}$	$T_j = 150 \text{ }^\circ\text{C}$	150	mJ	
I_{RRM}	$I_F = 600 \text{ A}$ $di/dt_{off} = 6100 \text{ A}/\mu\text{s}$	$T_j = 150 \text{ }^\circ\text{C}$	660	A	
Q_{rr}	$V_{GE} = -15 \text{ V}$ $V_R = 900 \text{ V}$	$T_j = 150 \text{ }^\circ\text{C}$	208	μC	
E_{rr}	$V_{GE} = -15 \text{ V}$ $V_R = 900 \text{ V}$	$T_j = 150 \text{ }^\circ\text{C}$	155	mJ	
$R_{th(j-c)}$	per diode			0.095	K/W
Module					
L_{CE}			22		nH
$R_{CC+EE'}$	res. terminal-chip	$T_C = 25 \text{ }^\circ\text{C}$ $T_C = 125 \text{ }^\circ\text{C}$	0.95 1.4		mΩ
$R_{th(c-s)}$	per module		0.03		K/W
M_s	to heat sink (M5)		3	5	Nm
M_t	to terminals (M6)		2.5	5	Nm
w				400	g
Temperature Sensor					
R_{100}	$T_c=100^\circ\text{C}$ ($R_{25}=5 \text{ k}\Omega$)		$493 \pm 5\%$		Ω
$B_{100/125}$	$R_{(T)}=R_{100}\exp[B_{100/125}(1/T-1/T_{100})]; T[\text{K}]$		3550 $\pm 2\%$		K



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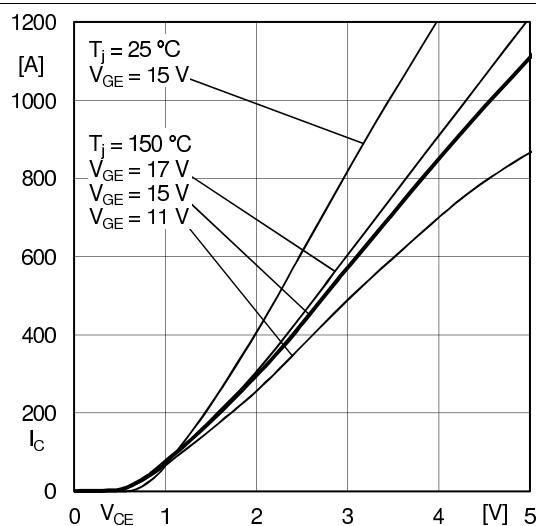


Fig. 1: Typ. output characteristic, inclusive $R_{CC} + EE$

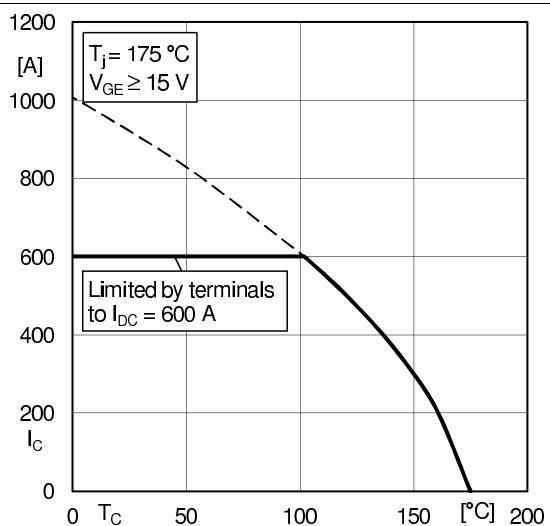


Fig. 2: Rated current vs. temperature $I_C = f(T_C)$

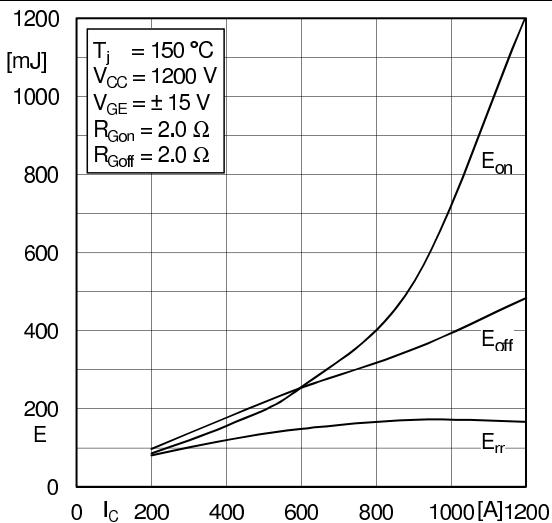


Fig. 3: Typ. turn-on /-off energy = $f(I_C)$

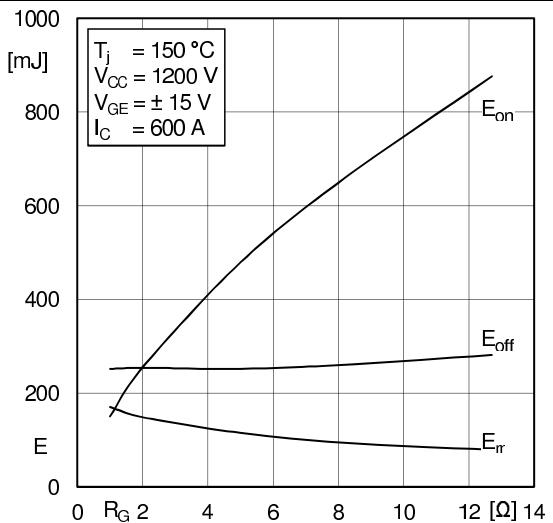


Fig. 4: Typ. turn-on /-off energy = $f(R_G)$

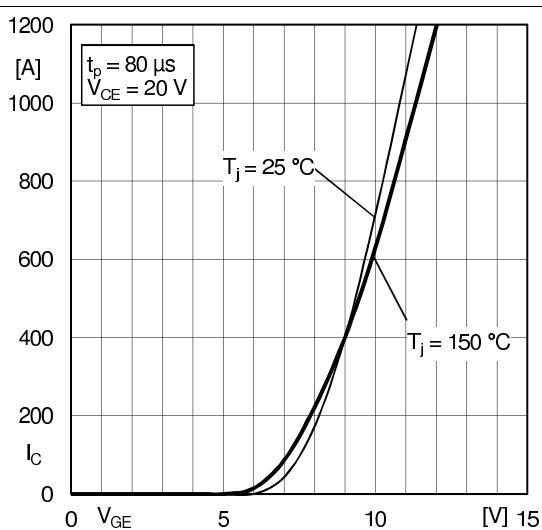


Fig. 5: Typ. transfer characteristic

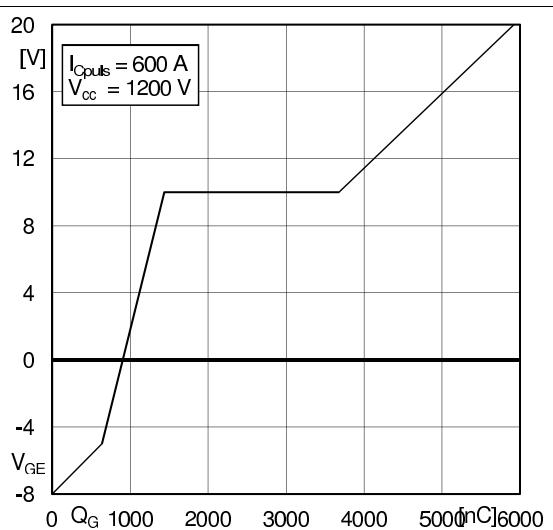


Fig. 6: Typ. gate charge characteristic

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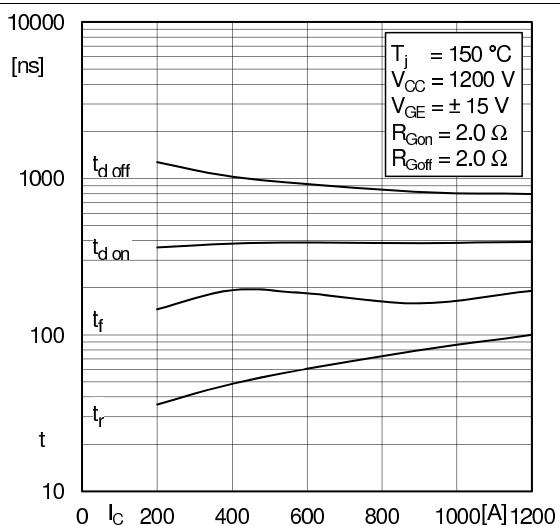


Fig. 7: Typ. switching times vs. I_C

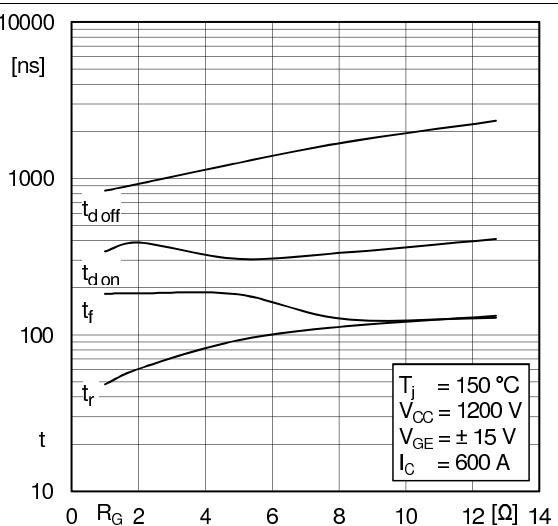


Fig. 8: Typ. switching times vs. gate resistor R_G

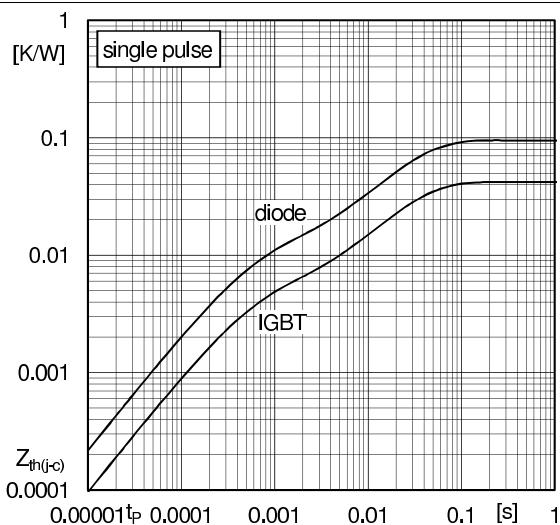


Fig. 9: Typ. transient thermal impedance

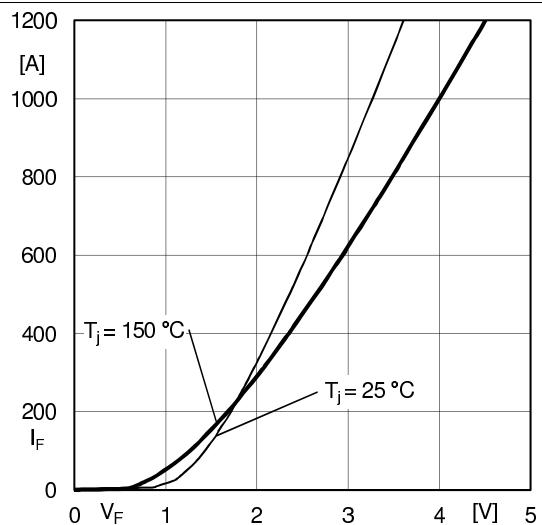


Fig. 10: Typ. CAL diode forward charact., incl. $R_{CC' + EE'}$

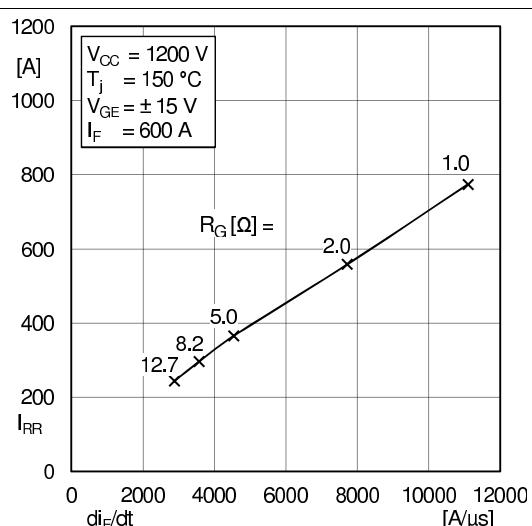


Fig. 11: Typ. CAL diode peak reverse recovery current

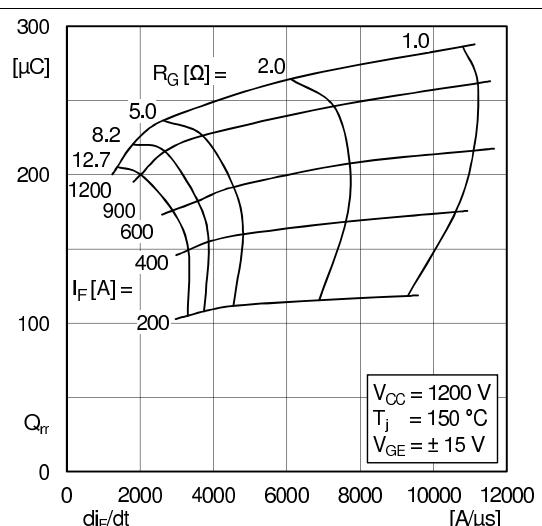
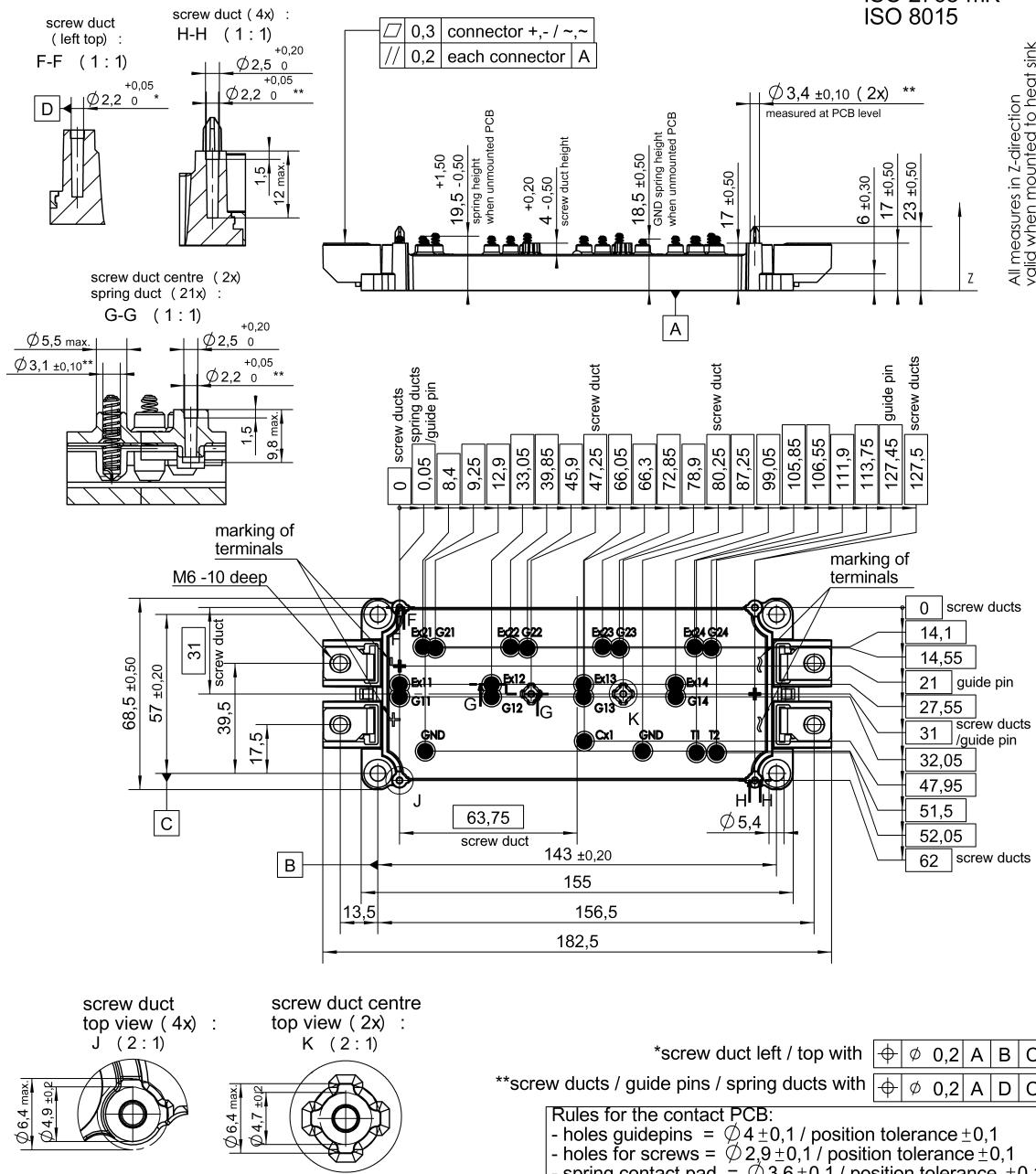


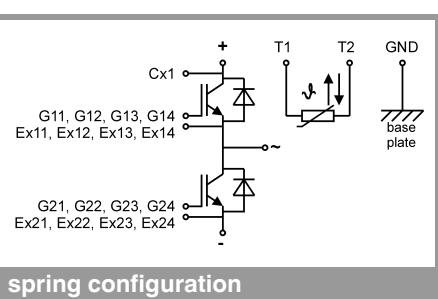
Fig. 12: Typ. CAL diode recovery charge

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Case: SEMiX 4s



SEMiX 4s



This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX

* The specifications of our components may not be considered as an assurance of component characteristics. Components have to be tested for the respective application. Adjustments may be necessary. The use of SEMIKRON products in life support appliances and systems is subject to prior specification and written approval by SEMIKRON. We therefore strongly recommend prior consultation of our staff.